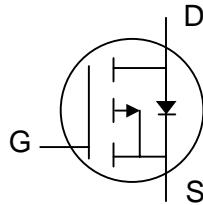


P-CHANNEL ENHANCEMENT-MODE POWER MOSFET

- Low gate-charge
- Simple drive requirement
- Fast switching

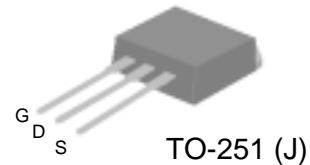
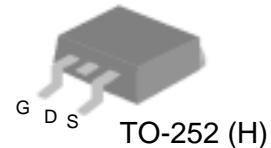


BV_{DSS}	-30V
$R_{DS(ON)}$	28mΩ
I_D	-30A

Description

The SSM40P03H is in a TO-252 package, which is widely used for commercial and industrial surface mount applications, and is well suited for low voltage applications such as DC/DC converters. The through-hole version, the SSM40P03J in TO-251, is available for low-footprint vertical mounting. These devices are manufactured with an advanced process, providing improved on-resistance and switching performance.

 Pb-free lead finish (second-level interconnect)



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-30	A
$I_D @ T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-18	A
I_{DM}	Pulsed Drain Current ¹	-120	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation	31.3	W
	Linear Derating Factor	0.25	W/°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Thermal Resistance Junction-case	Max. 4.0	°C/W
R_{thj-a}	Thermal Resistance Junction-ambient	Max. 110	°C/W

Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=-1\text{mA}$	-	-0.02	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-18\text{A}$	-	-	28	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-14\text{A}$	-	-	50	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=-250\mu\text{A}$	-1	-	-	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$, $I_{\text{D}}=-18\text{A}$	-	20	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=-30\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-1	μA
	Drain-Source Leakage Current ($T_j=150^\circ\text{C}$)	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-25	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_{\text{D}}=-18\text{A}$	-	14	22	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-24\text{V}$	-	3	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	9	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time ²	$V_{\text{DS}}=-15\text{V}$	-	12	-	ns
t_r	Rise Time	$I_{\text{D}}=-18\text{A}$	-	56	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=-10\text{V}$	-	30	-	ns
t_f	Fall Time	$R_D=0.8\Omega$	-	57	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	915	1465	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	280	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	195	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=-18\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time ²	$I_{\text{S}}=-18\text{A}$, $V_{\text{GS}}=0\text{V}$,	-	30	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=-100\text{A}/\mu\text{s}$	-	21	-	nC

Notes:

- 1.Pulse width limited by safe operating area.
- 2.Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.

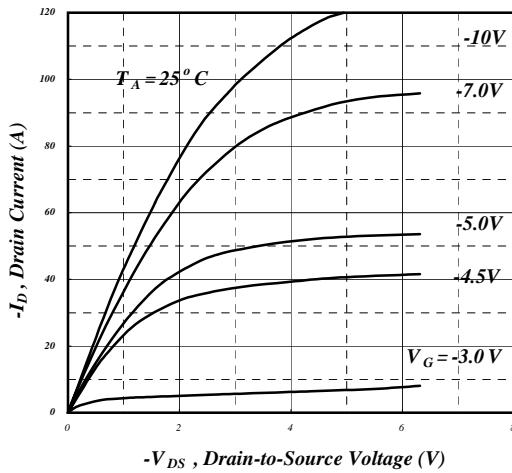


Fig 1. Typical Output Characteristics

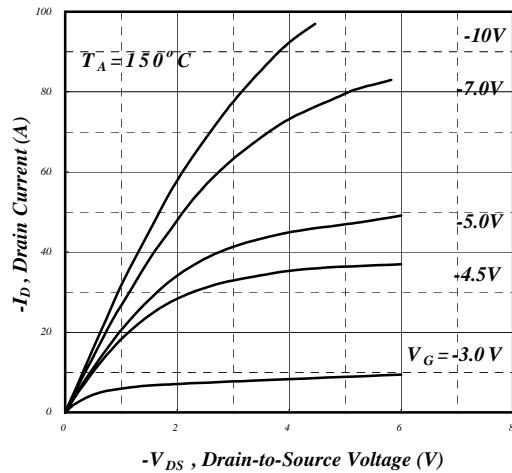


Fig 2. Typical Output Characteristics

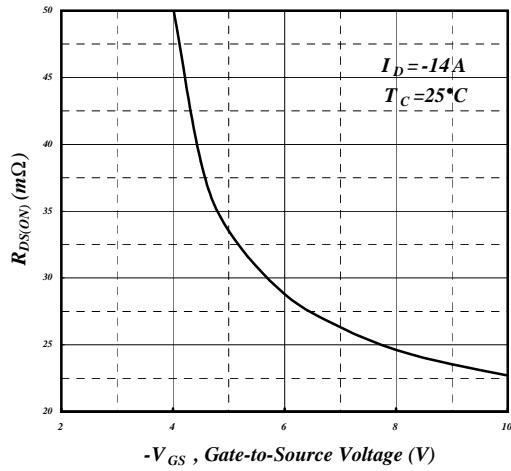


Fig 3. On-Resistance vs. Gate Voltage

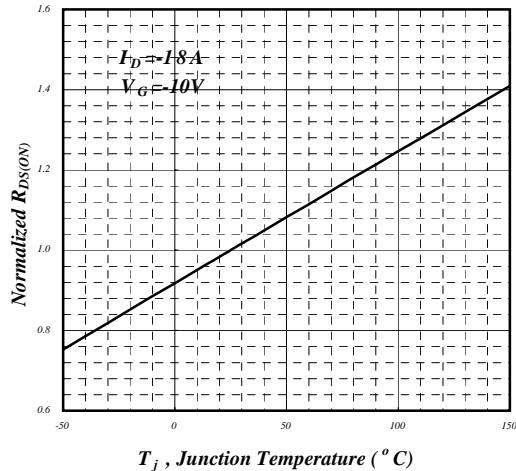


Fig 4. Normalized On-Resistance vs. Junction Temperature

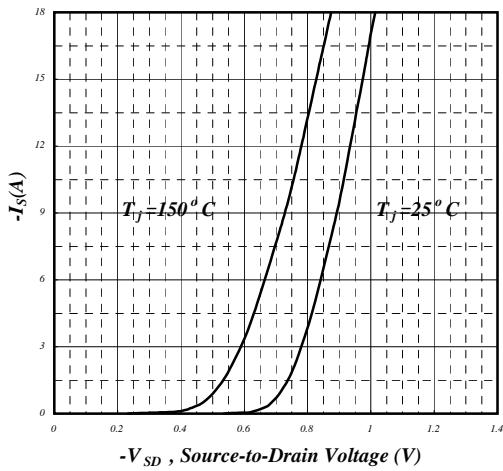


Fig 5. Forward Characteristic of Reverse Diode

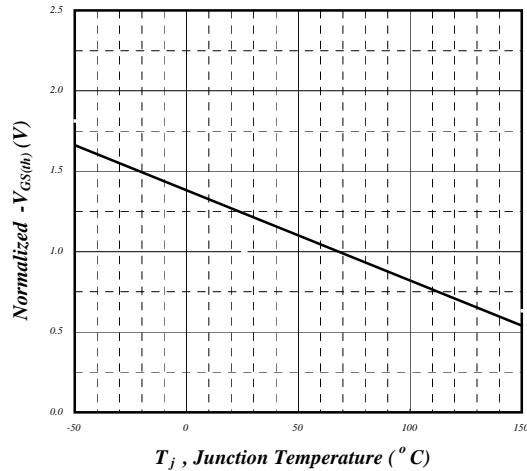


Fig 6. Gate Threshold Voltage vs. Junction Temperature

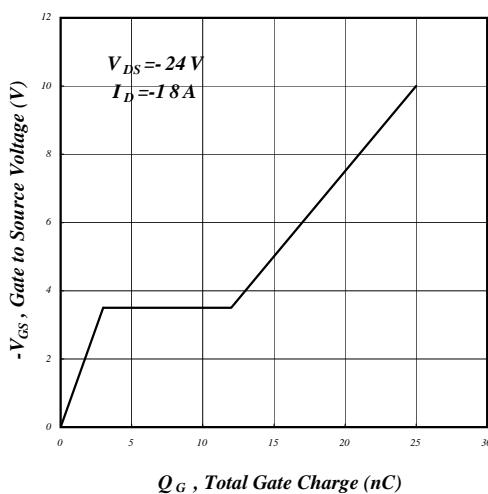


Fig 7. Gate Charge Characteristics

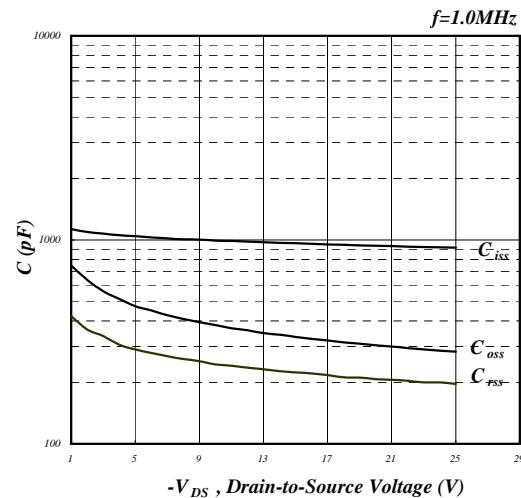


Fig 8. Typical Capacitance Characteristics

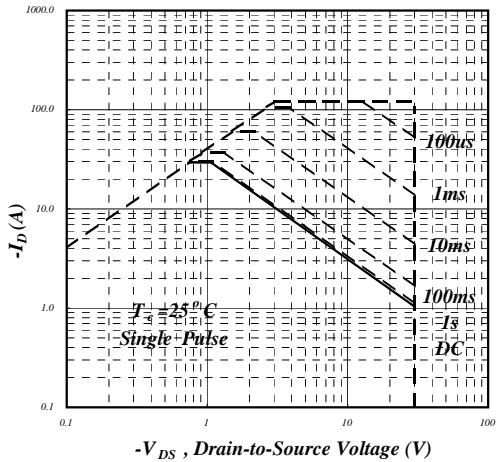


Fig 9. Maximum Safe Operating Area

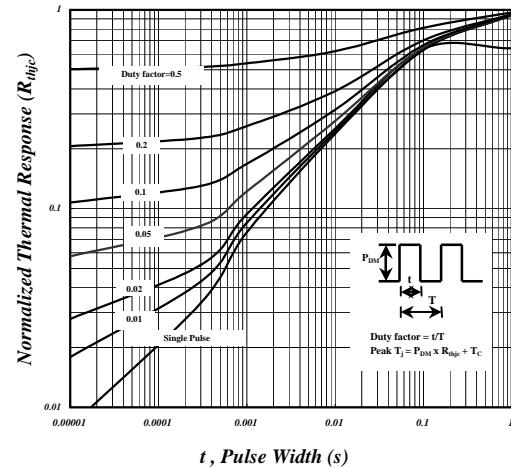


Fig 10. Effective Transient Thermal Impedance

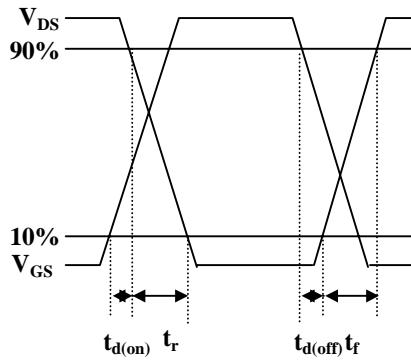


Fig 11. Switching Time Waveform

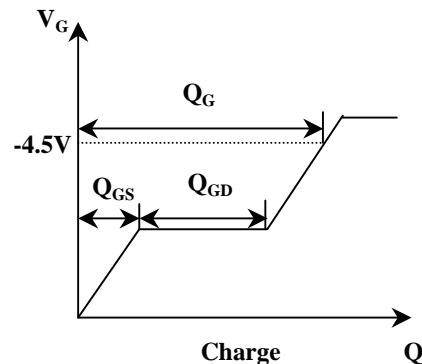


Fig 12. Gate Charge Waveform

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